

Special Issue on X-Ray Diffraction

Call for Papers

X-ray Diffraction (XRD) is one of the primary techniques used by mineralogists and solid state chemists to examine the physico-chemical make-up of unknown solids. This data is represented in a collection of single-phase X-ray powder diffraction patterns for the three most intense D values in the form of tables of interplanar spacings (D), relative intensities (I/I_0), and mineral name.

The XRD technique takes a sample of the material and places a powdered sample in a holder, then the sample is illuminated with x-rays of a fixed wave-length and the intensity of the reflected radiation is recorded using a goniometer. This data is then analyzed for the reflection angle to calculate the inter-atomic spacing (D value in Angstrom units - 10^{-8} cm). The intensity(I) is measured to discriminate (using I ratios) the various D spacings and the results are to identify possible matches.

In this special issue, we intend to invite front-line researchers and authors to submit original research and review articles on exploring **X-Ray Diffraction**.

Authors should read over the journal's [Author's Guidelines](#) carefully before submission, Prospective authors should submit an electronic copy of their complete manuscript through the journal [Paper Submission System](#).

Please kindly notice that the "**Special Issue**" under your manuscript title is supposed to be specified and the research field "**Special Issue-X-Ray Diffraction**" should be chosen during your submission.

According to the following timetable:

Manuscript Due	February 20th, 2013
Publication Date	April, 2013

Editor-in-Chief

Prof. **Zhiwen Chen**
Shanghai University, China

For further questions or inquiries
Please contact Editorial Assistant at
ampc@scirp.org

